

Erik Jonsson School of Engineering and Computer Science

15.6 A 10MHz i-Collapse Failure Self-Prognostic GaN Power Converter with TJ -Independent In-Situ Condition Monitoring and Proactive Temperature Frequency Scaling

UT Dallas Author(s):

Yingping Chen
Dongsheng (Brian) Ma

Citation:

Chen, Y., and D. B. Ma. 2019. "15.6 A 10MHz i-Collapse Failure Self-Prognostic GaN Power Converter with TJ-Independent In-Situ Condition Monitoring and Proactive Temperature Frequency Scaling." Digest of Technical Papers - IEEE International Solid-State Circuits Conference: 248-250, doi: 10.1109/ISSCC.2019.8662527

Access to full text is restricted to users with a valid UT Dallas NetID and password. Authorized users may click the link below to gain entry into the publisher's website.

<http://utd.edu/t/5280>